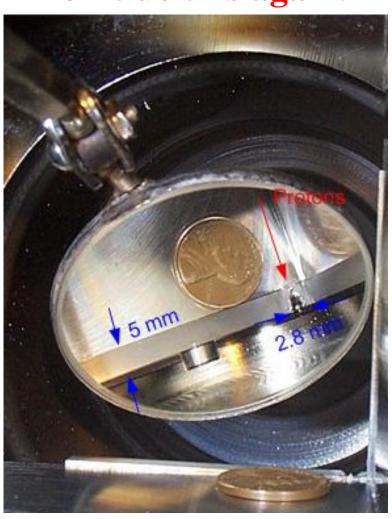
# **Beam Loss Monitor Upgrade**

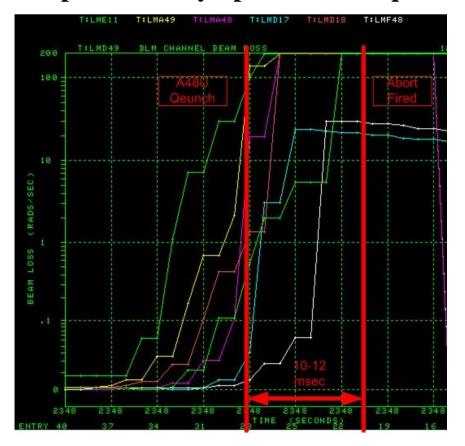
J. Lewis
All Experimenters' Meeting
2 May 2005

### **Motivation**

### • Don't do this again.



### Loss profile: Tokyo-pot 16-house quench



# **Response: Abort Upgrade**

- New Loss Monitor electronics
  - Abort logic designed for collider operations
  - Improved diagnostic capabilities
- Improvements to QPM
  - Faster response
  - Running many months
  - Ask the Tevatron guys for details

### **Further Motivation**

- Scope broadened to improve high-intensity proton operations
- Tevatron
  - Protect magnets from beam-induced quenches
  - Legacy system is not sufficiently flexible to use during complex operations cycle
    - Designed for fast-cycle fixed-target operations

### Main Injector

- Greater diagnostic capability needed for high-intensity operation
  - Limit activation of accelerator components
  - Intensity 5x greater with NUMI operation
  - Maximize proton flux

#### Booster

- Improved diagnostics
  - Limit activation
  - Maximize flux

# **Existing System Characteristics and Limitations**

### Signal properties

- Good resolution and dynamic range
- Fast leading edge response, slow discharge

#### Tevatron Aborts

- Fast:  $\sim 50-100$  μs
- Fires on single channel over threshold
- Minimal compatibility with multiple machine configurations
  - Two abort levels, high and low field
  - Abort disabled when antiprotons are in the machine

#### Read out

- Updates slowly: ~ 3 ms period
- Fast access to one channel per chassis
  - 24 signals multiplexed in MI

#### Difficult to enhance and maintain

- 23 years old
- Read out via Multibus(!) with obsolete software

# Requirements for New System

- Robustness: No false aborts
- Reliability: No missed aborts
- Respond to changing machine configurations
- Access to data from all channels
- Maintain resolution
  - System designed around low-noise integrator
- Large dynamic range
  - 0.02 Rad/s in 1 ms to 100 Rad in a single turn
- Good time resolution and depth
  - Multiple integration periods, each with >4k sample history
- Include experiments in Tevatron BLM system
  - Two Camac crates with special electronics hard to maintain

# **System Overview**

- Integrate BLM current and digitize every ~20 μs
  - Tevatron turn frequency or MI frequency ÷2
- Form three running sums for additional integration periods
  - Programmable time constants
    - Example: 1ms, 50ms, 1s
  - Maintain history of >4000 cycles for each period
    - Also 8k injection turn-by-turn
  - Also record integrated loss through each MI cycle
- One abort threshold per integration period for each channel
- Abort requirements changed in response to machine states
  - Thresholds, masks, multiplicities
- Safe operation
  - Isolated from VME and Ethernet
    - Embedded microprocessor
    - Custom local bus on J2

# **Components**

### Digitizer Card

- 4 integrator channels
  - Deadtimeless operation
- Form running sums
- Compare to thresholds
- Raw data buffers
- Max 15 per crate

### Timing Card

- Provides synchronous clock
- Keeps time buffers
- Decodes machine clock events

### High Voltage Card

Power up to 60 channels

#### Control Card

- Keeps diagnostic data
  - Running sum data
- Updates abort requirements on state changes

#### Abort Card

- Reads abort data from Digitizers
- Compares to mask and multiplicity requirement

#### Crate

- Wiener 6U VME chassis
- Low-noise power supply
- Custom J2 backplane

### **Status**

- Digitizer
  - Extensive standalone testing of prototype
  - Updating design to extend functionality
- Timing Card
  - Testing prototype
- Crate
  - All received.
- Abort and HV Cards
  - Design nearly complete
- Controller
  - Firmware working in simulation
  - Card schematic done

### **Personnel**

- Alan Baumbaugh (PPD/EED)
  - System design, Control card software
- Kelly Knickerbocker (PPD/EED)
  - Timing card, infrastructure
- Craig Drennan (AD/BS)
  - Digitizer
- Marvin Olson (AD/ID)
  - System support
- Cecil Needles (PPD/EED)
  - Digitizer Firmware
- Mike Utes (PPD/EED)
  - Abort Card

- Jonathan Lewis (PPD/CDF)
  - Management
- Stephen Pordes (AD/ID)
  - Wisdom and advice (solicited or otherwise)
- Randy Keup (AD/ID)
  - Applications programs
- Brian Fellenz (AD)
  - HV card
- Jin-Yuan Wu (PPD/EED)
  - Control Card
- Charlie Briegel, Brian Hendricks (AD/Controls)

# **Schedule**

- Beam tests starting soon
  - Can do extensive testing with VME readout before Controller complete
    - Pre-production Digitizer, Controller and Abort card added in June
  - Duplicate BLMs to compare to legacy system
    - Tevatron: 6 at E1
    - Main Injector: 2 at MI60
  - Develop and test software
  - Get operational experience
- July 2005: Preproduction test
- Install crates when old BPM electronics removed
  - Get host CPUs running ASAP

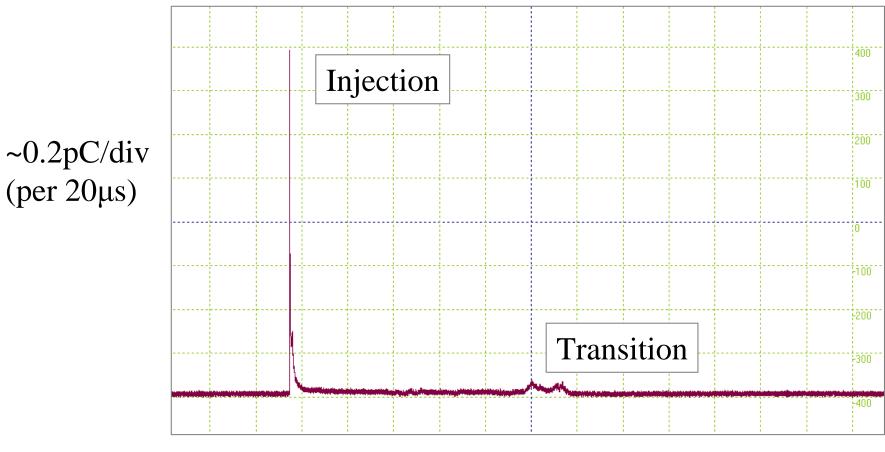
### **Installation Schedule**

- Modules available to install in November
  - Tevatron and MI
- Can install new system without removing old
  - Easy cabling changeover
- Can establish operations with small fraction of channels then move balance of cables

# Experience

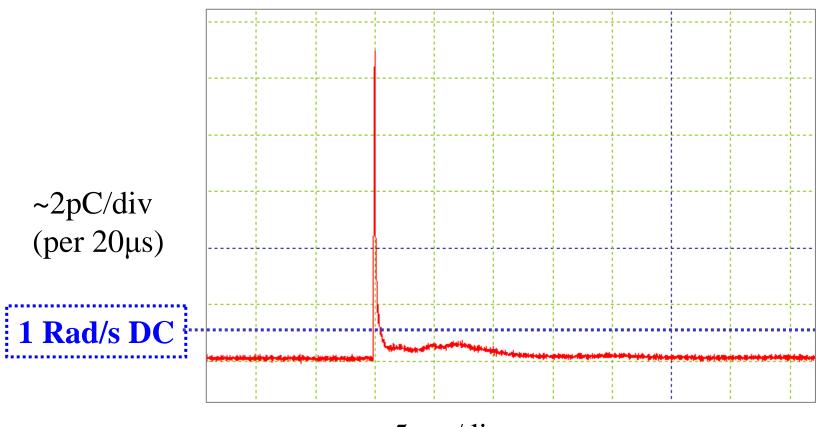
- Studies with 2-channel digitizer test card
- Understand signals and noise
  - Selected sites in Tevatron, MI and Booster
- Check calibration for Tevatron
  - Old system:  $50nA \leftrightarrow 0.84 \text{ Rad/s}$  (1 Rad  $\leftrightarrow 60nC$ )
  - New system:  $50nA \leftrightarrow 56$  counts (20µs bins)
- Explored noise suppression
  - Wide channel-to-channel variation
  - Filters
    - Chokes for common mode
    - Resistor to increase effective integration time
  - Running sums

# MI: LM402G full cycle



25 ms/div

### **Tevatron: LMF0DT**

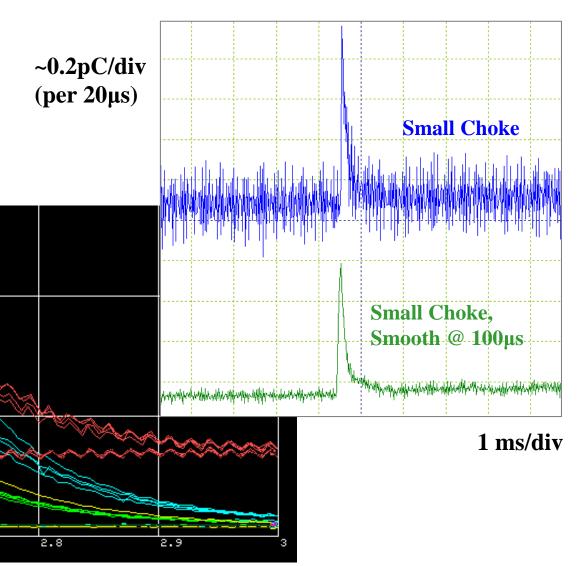


5 ms/div

### **Proton Injection Loss During Shot Setup 8/22/04**

### LMF12: Old and New

Losses in F-sector from 120 GeV beamline during stacking



100 ms/div

**LMF 12** 

per div

0.025 R/s

### **Conclusions**

- In past year, we have completed most of the design work for a new BLM readout system
- Improved diagnostics will improve accelerator performance
- Greater flexibility will enable better protection of equipment
- Expected to be online February 2006

# **Backup Slides**

# **Custom Digitizer Card**

#### 4 Loss Monitor Channels

- Dual Charge Integrator (Burr Brown ACF2101)
  - Alternately integrating or being readout and reset
  - Provides continuous measurement
  - 50 kHz maximum sample rate

#### FPGA

- Controls integrators
- Reads ADCs
- Stores readings (raw measurements)
- Forms three running sums
- Compares readings and sums to programmed thresholds
  - Results sent to Abort Card

#### Raw data buffers

- Running circular buffer
- Triggered buffer for turn-by-turn studies
- Maximum 15 cards per crate

### **Other Modules**

### Timing Card

- Provides synchronous integration clock to digitizers
  - External input Clock reference or internal oscillator
  - Can also be divided (e.g. AA÷2 for MI)
- Time stamp buffer in sync with the digitizers' raw data buffers
- Decoder to receive clock events

#### Abort Card

- Receives abort info from the digitizer cards, compares against abort masks and multiplicities and makes the abort signals
- One abort input for each time-range from each channel
- Separate decisions for each time-range
  - Independent masks and multiplicity thresholds
- Aborts are formed in < 20 microseconds</li>
- Also transmits abort data on ring-wide serial link

# Other Modules, 2

- Controller Card
  - Communicates with other cards on control bus
    - Bus master
  - Isolates Abort functions from outside world
    - FPGA VME slave and control-bus eZ80 access shared memory
      - Stores loss data buffers for running sums and provides to VME
      - Stores BLM thresholds and abort requirements for each machine state
    - Loads parameters into digitizer and abort concentrator cards based on machine state
- Front-end CPU
  - Motorola MVME 2xxx for communication with ACNET
- High Voltage Card
- Wiener VME Chassis with low-noise power supply

# **Proposed Machine States**

### Tevatron Operation

- Proton Studies (i.e. uncoalesced batch at 150)
- Proton Injection
- Activate Separators
- Pbar Injection
- Ramp
- Squeeze
- Scraping
- HEP

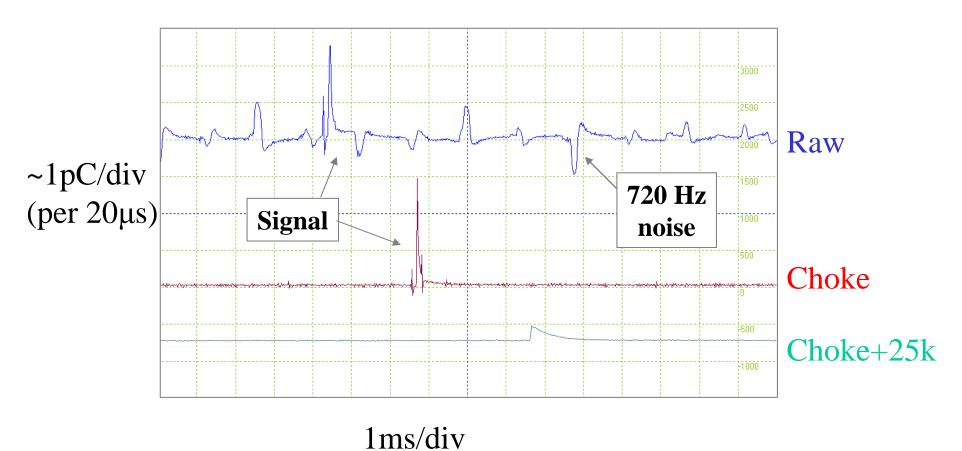
### • F Sector (change mask)

- P2 Beam
- P2 & P3 Beam
- F-Sector Restore

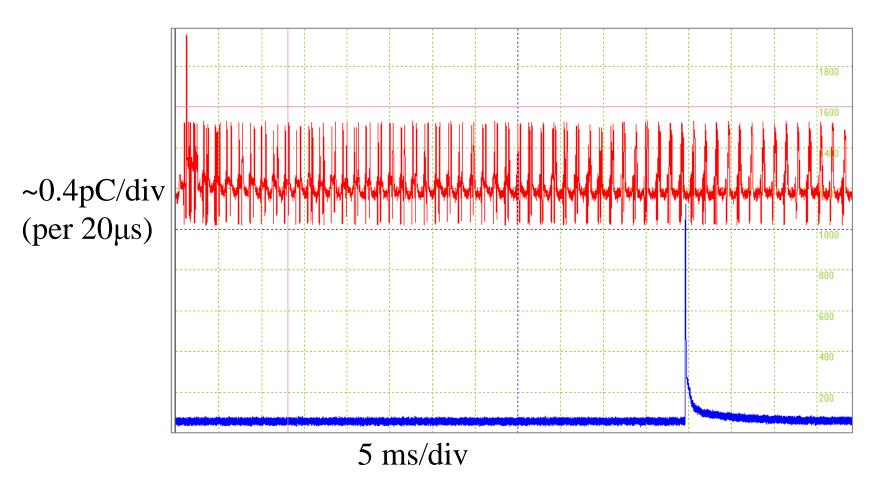
### Experiments

- CDF Silicon Biased
- CDF Silicon Off
- D0 Silicon Biased
- D0 Silicon Off

# **Booster: LM23**

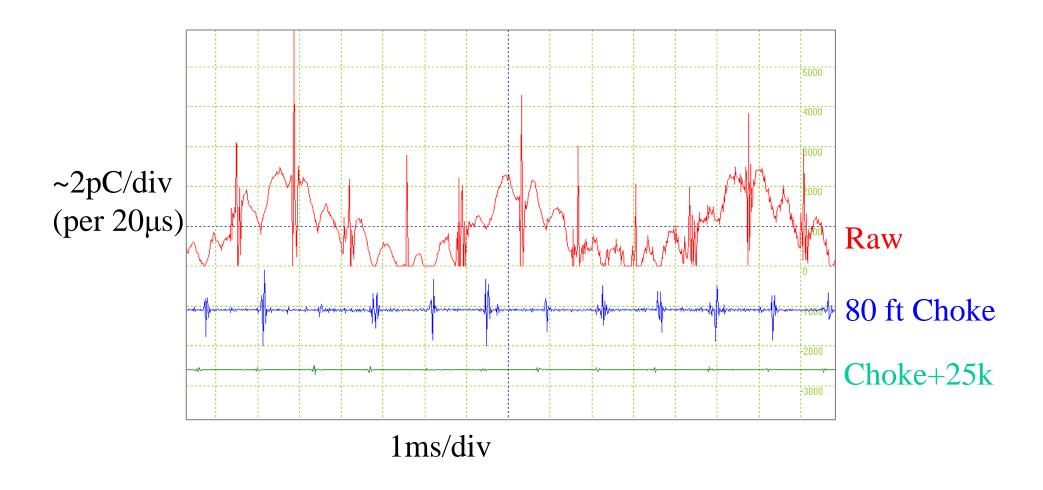


# **MI: LM402G**

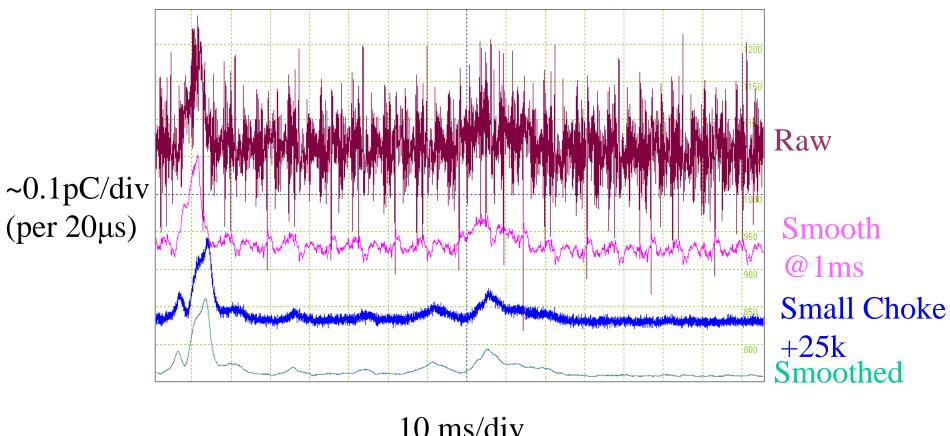


- •Large common-mode rejection from small choke
- Injection loss shows up cleanly

# **Worst Case Noise: LM322**



# **Smoothing: LM522F**



10 ms/div

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